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| File Attributes Record (FAR) | |  |  |
| Contains the information necessary to determine how to decode the STDF data contained in the file.  包含确定如何解码文件中所含 STDF 数据的必要信息。 | | | |
| **Field Name** | **Data Type** | **Field Description** | **Istar** |
| REC\_LEN | U\*2 | Bytes of data following header |  |
| REC\_TYP | U\*1 | Record typ (0) |  |
| REC\_SUB | U\*1 | Record sub-type (10) |  |
|  | | | |
| CPU\_TYPE | U\*1 | CPU type that wrote this file | 2 |
| STDF\_VER | U\*1 | STDF version number | 4 |

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| Master Information Record (MIR) | |  |  |  |
| The MIR and the MRR (Master Results Record) contain all the global information that is to be stored for a tested lot of parts. Each data stream must have exactly one MIR, immediately after the FAR (and the ATRs, if they are used). This will allow any data reporting or analysis programs access to this information in the shortest possible amount of time.  MIR 和 MRR（主结果记录）包含要存储的测试批次部件的所有全局信息。每个数据流必须有一个准确的 MIR，紧接在 FAR（和 ATR，如果使用的话）之后。这样，任何数据报告或分析程序都能在最短时间内访问这些信息。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (1) |  |  |
| REC\_SUB | U\*1 | Record sub-type (10) |  |  |
|  | | | | |
| SETUP\_T | U\*4 | Date and time of job setup | V | Raw |
| START\_T | U\*4 | Date and time first part tested | V | Raw |
| STAT\_NUM | U\*1 | Tester station number | V | Default 0 (chassis number?) |
| MODE\_COD | C\*1 | Test mode code (e.g. prod, dev) | V | LotInformations |
| RTST\_COD | C\*1 | Lot retest code | V | LotInformations |
| PROT\_COD | C\*1 | Data protection code | V | LotInformations |
| BURN\_TIM | U\*2 | Burn-in time (in minutes) | V | LotInformations |
| CMOD\_COD | C\*1 | Command mode code | V | LotInformations |
| LOT\_ID | C\*n | Lot ID (customer specified) | V | LotInformations |
| PART\_TYP | C\*n | Part Type (or product ID) | V | LotInformations |
| NODE\_NAM | C\*n | Name of node that generated data | V | LotInformations |
| TSTR\_TYP | C\*n | Tester type | V | LotInformations |
| JOB\_NAM | C\*n | Job name (test program name) | V | LotInformations |
| JOB\_REV | C\*n | Job (test program) revision number | V | LotInformations |
| SBLOT\_ID | C\*n | Sublot ID | V | LotInformations |
| OPER\_NAM | C\*n | Operator name or ID (at setup time) | V | LotInformations |
| EXEC\_TYP | C\*n | Tester executive software type | V | LotInformations |
| EXEC\_VER | C\*n | Tester exec software version number | V | LotInformations |
| TEST\_COD | C\*n | Test phase or step code | V | LotInformations |
| TST\_TEMP | C\*n | Test temperature | V | LotInformations |
| USER\_TXT | C\*n | Generic user text | V | LotInformations |
| AUX\_FILE | C\*n | Name of auxiliary data file | V | LotInformations |
| PKG\_TYP | C\*n | Package type | V | LotInformations |
| FAMLY\_ID | C\*n | Product family ID | V | LotInformations |
| DATE\_COD | C\*n | Date code | V | LotInformations |
| FACIL\_ID | C\*n | Test facility ID | V | LotInformations |
| FLOOR\_ID | C\*n | Test floor ID | V | LotInformations |
| PROC\_ID | C\*n | Fabrication process ID | V | LotInformations |
| OPER\_FRQ | C\*n | Operation frequency or step | V | LotInformations |
| SPEC\_NAM | C\*n | Test specification name | V | LotInformations |
| SPEC\_VER | C\*n | Test specification version number | V | LotInformations |
| FLOW\_ID | C\*n | Test flow ID | V | LotInformations |
| SETUP\_ID | C\*n | Test setup ID | V | LotInformations |
| DSGN\_REV | C\*n | Device design revision | V | LotInformations |
| ENG\_ID | C\*n | Engineering lot ID | V | LotInformations |
| ROM\_COD | C\*n | ROM code ID | V | LotInformations |
| SERL\_NUM | C\*n | Tester serial number | V | LotInformations |
| SUPR\_NAM | C\*n | Supervisor name or ID | V | LotInformations |

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| Master Results Record (MRR) | |  |  |  |
| The Master Results Record (MRR) is a logical extension of the Master Information Record (MIR). The data can be thought of as belonging with the MIR, but it is not available when the tester writes the MIR information. Each data stream must have exactly one MRR as the last record in the data stream.  主结果记录（MRR）是主信息记录（MIR）的逻辑延伸。可以认为这些数据属于 MIR，但在测试人员写入 MIR 信息时，这些数据不可用。每个数据流必须有一条 MRR 作为数据流中的最后一条记录。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (1) |  |  |
| REC\_SUB | U\*1 | Record sub-type (20) |  |  |
|  | | | | |
| FINISH\_T | U\*4 | Date and time last part tested | V | Raw |
| DISP\_COD | C\*1 | Lot disposition code |  |  |
| USR\_DESC | C\*n | Lot description supplied by user |  |  |
| EXC\_DESC | C\*n | Lot description supplied by exec |  |  |

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| Part Count Record (PCR) |  |  |  |  |
| Contains the part count totals for one or all test sites. Each data stream must have at least one PCR to show the part count.  包含一个或所有测试点的部件总数。每个数据流必须至少有一个 PCR 才能显示部件数。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (1) |  |  |
| REC\_SUB | U\*1 | Record sub-type (30) |  |  |
|  | | | | |
| HEAD\_NUM | U\*1 | Test head number | V | Default(1) |
| SITE\_NUM | U\*1 | Test site number | V | Raw |
| PART\_CNT | U\*4 | Number of parts tested | V | Raw |
| RTST\_CNT | U\*4 | Number of parts retested |  |  |
| ABRT\_CNT | U\*4 | Number of aborts during testing |  |  |
| GOOD\_CNT | U\*4 | Number of good (passed) parts tested |  |  |
| FUNC\_CNT | U\*4 | Number of functional parts tested |  |  |

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| Hardware Bin Record (HBR) | |  |  |  |
| Stores a count of the parts “physically” placed in a particular bin after testing. (In wafer testing, “physical” binning is not an actual transfer of the chip, but rather is represented by a drop of ink or an entry in a wafer map file.) This bin count can be for a single test site (when parallel testing) or a total for all test sites. The STDF specification also supports a Software Bin Record (SBR) for logical binning categories. A part is “physically” placed in a hardware bin after testing. A part can be “logically” associated with a software bin during or after testing.  存储测试后 "物理 "放入特定分仓的部件数量。(在晶圆测试中，"物理 "分仓并不是芯片的实际转移，而是由一滴墨水或晶圆映射文件中的一个条目来表示）。该分选计数可以是单个测试点的计数（并行测试时），也可以是所有测试点的总计数。STDF 规范还支持用于逻辑分选类别的软件分选记录 (SBR)。一个部件在测试后被 "物理 "地放入一个硬件分仓。在测试过程中或测试后，一个部件可以 "逻辑 "地与一个软件分仓相关联。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (1) |  |  |
| REC\_SUB | U\*1 | Record sub-type (40) |  |  |
|  | | | | |
| HEAD\_NUM | U\*1 | Test head number | V | Default(1) |
| SITE\_NUM | U\*1 | Test site number | V | Raw |
| HBIN\_NUM | U\*2 | Hardware bin number | V | BinResult.HwBin |
| HBIN\_CNT | U\*4 | Number of parts in bin | V | Raw |
| HBIN\_PF | C\*1 | Pass/fail indication | V | TestItemResult.Result |
| HBIN\_NAM | C\*n | Name of hardware bin |  |  |

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| Software Bin Record (SBR) | |  |  |  |
| Stores a count of the parts associated with a particular logical bin after testing. This bin count can be for a single test site (when parallel testing) or a total for all test sites. The STDF specification also supports a Hardware Bin Record (HBR) for actual physical binning. A part is “physically” placed in a hardware bin after testing. A part can be “logically” associated with a software bin during or after testing.  存储测试后与特定逻辑仓相关的部件计数。该分仓计数可以是单个测试点（并行测试时）的计数，也可以是所有测试点的总计数。STDF 规范还支持用于实际物理分仓的硬件分仓记录（HBR）。一个部件在测试后被 "物理 "地放入一个硬件分仓。在测试过程中或测试后，一个部件可以 "逻辑 "地与一个软件分仓相关联。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (1) |  |  |
| REC\_SUB | U\*1 | Record sub-type (50) |  |  |
|  | | | | |
| HEAD\_NUM | U\*1 | Test head number | V | Default(1) |
| SITE\_NUM | U\*1 | Test site number | V | Raw |
| SBIN\_NUM | U\*2 | Software bin number | V | BinResult.HwBin |
| SBIN\_CNT | U\*4 | Number of parts in bin | V | Raw |
| SBIN\_PF | C\*1 | Pass/fail indication | V | TestItemResult.Result |
| SBIN\_NAM | C\*n | Name of software bin |  |  |

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| Pin Map Record (PMR) |  |  |  |  |
| Provides indexing of tester channel names, and maps them to physical and logical pin names. Each PMR defines the information for a single channel/pin combination.  为测试仪通道名称提供索引，并将其映射到物理和逻辑引脚名称。每个 PMR 定义一个通道/引脚组合的信息。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (1) |  |  |
| REC\_SUB | U\*1 | Record sub-type (60) |  |  |
|  | | | |  |
| PMR\_INDX | U\*2 | Unique index associated with pin | v | ChannelInformation.Pindex |
| CHAN\_TYP | U\*2 | Channel type |  |  |
| CHAN\_NAM | C\*n | Channel name |  |  |
| PHY\_NAM | C\*n | Physical name of pin | v | ChannelInformation.PinName |
| LOG\_NAM | C\*n | Logical name of pin | v | ChannelInformation.PinNum |
| HEAD\_NUM | U\*1 | Head number associated with channel |  |  |
| SITE\_NUM | U\*1 | Site number associated with channel |  |  |

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| Part Information Record (PIR) | |  |  |  |
| Acts as a marker to indicate where testing of a particular part begins for each part tested by the test program. The PIR and the Part Results Record (PRR) bracket all the stored information pertaining to one tested part.  对于测试程序测试的每个部件，作为标记指示特定部件测试的开始位置。部件清单（PIR）和部件结果记录（PRR）包含与一个测试部件相关的所有存储信息。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (5) |  |  |
| REC\_SUB | U\*1 | Record sub-type (10) |  |  |
|  | | | | |
| HEAD\_NUM | U\*1 | Test head number | V | Default(1) |
| SITE\_NUM | U\*1 | Test site number | V | Raw |

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| Part Results Record (PRR) |  |  |  |  |
| Contains the result information relating to each part tested by the test program. The PRR and the Part Information Record (PIR) bracket all the stored information pertaining to one tested part.  包含与测试程序测试的每个部件相关的结果信息。部件信息记录（PRR）和部件信息记录（PIR）包含与一个测试部件相关的所有存储信息。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (5) |  |  |
| REC\_SUB | U\*1 | Record sub-type (20) |  |  |
|  | | | | |
| HEAD\_NUM | U\*1 | Test head number | V | Default(1) |
| SITE\_NUM | U\*1 | Test site number | V | Raw |
| PART\_FLG | B\*1 | Part information flag |  |  |
| NUM\_TEST | U\*2 | Number of tests executed | V | TestResult.TesiItemResults.Count |
| HARD\_BIN | U\*2 | Hardware bin number | V | TestResult.BinResult.HwBin |
| SOFT\_BIN | U\*2 | Software bin number | V | TestResult.BinResult.SwBin |
| X\_COORD | I\*2 | (Wafer) X coordinate | V | XCoordinate |
| Y\_COORD | I\*2 | (Wafer) Y coordinate | V | YCoordinate |
| TEST\_T | U\*4 | Elapsed test time in milliseconds | V | TestResult.FlowTestTimes.TestTime |
| PART\_ID | C\*n | Part identification | V | TestResult.SerialNumbers |
| PART\_TXT | C\*n | Part description text |  |  |
| PART\_FIX | B\*n | Part repair information |  |  |

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| Test Synopsis Record（TSR） |  |  |  |  |
| Contains the test execution and failure counts for one parametric or functional test in the test program. Also contains static information, such as test name. The TSR is related to the Functional Test Record (FTR), the Parametric Test Record (PTR), and the Multiple Parametric Test Record (MPR) by test number, head number, and site number.  包含测试程序中一个参数或功能测试的测试执行和失败次数。还包含静态信息，如测试名称。TSR 与功能测试记录 (FTR)、参数测试记录 (PTR) 和多参数测试记录 (MPR) 之间的关系是通过测试编号、组长编号和站点编号来确定的。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (10) |  |  |
| REC\_SUB | U\*1 | Record sub-type (30) |  |  |
|  | | | | |
| HEAD\_NUM | U\*1 | Test head number | V | Default(255) |
| SITE\_NUM | U\*1 | Test site number | V | Default(255) |
| TEST\_TYP | C\*1 | Test type | V | TestItemResult.TestType |
| TEST\_NUM | U\*4 | Test number | V | TestItemResult.TestNumber |
| EXEC\_CNT | U\*4 | Number of test executions | V | Raw |
| FAIL\_CNT | U\*4 | Number of test failures | V | Raw |
| ALRM\_CNT | U\*4 | Number of alarmed tests | V | Default(0) |
| TEST\_NAM | C\*n | Test name | V | TestItemResult.PinName |
| SEQ\_NAME | C\*n | Sequencer (program segment/flow) name |  |  |
| TEST\_LBL | C\*n | Test label or text |  |  |
| OPT\_FLAG | B\*1 | Optional data flag |  |  |
| TEST\_TIM | R\*4 | Average test execution time in seconds | V | TestItemResult.TestTime/ExcutedCount |
| TEST\_MIN | R\*4 | Lowest test result value |  |  |
| TEST\_MAX | R\*4 | Highest test result value |  |  |
| TST\_SUMS | R\*4 | Sum of test result values |  |  |
| TST\_SQRS | R\*4 | Sum of squares of test result values |  |  |

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| Parametric Test Record (PTR) | |  |  |  |
| Contains the results of a single execution of a parametric test in the test program. The first occurrence of this record also establishes the default values for all semi-static information about the test, such as limits, units, and scaling. The PTR is related to the Test Synopsis Record (TSR) by test number, head number, and site number.  包含测试程序中参数测试的单次执行结果。该记录的首次出现也为测试的所有半静态信息（如极限、单位和比例）确定了默认值。PTR 与测试概要记录（TSR）之间的关系是测试编号、试验头编号和试验场编号。 | | | |  |
| **Field Name** | **Data Type** | **Field Description** | **Istar** | **Source** |
| REC\_LEN | U\*2 | Bytes of data following header |  |  |
| REC\_TYP | U\*1 | Record typ (15) |  |  |
| REC\_SUB | U\*1 | Record sub-type (10) |  |  |
|  | | | | |
| TEST\_NUM | U\*4 | Test number | V | TestItemResult.TesterNumber |
| HEAD\_NUM | U\*1 | Test head number | V | Default(1) |
| SITE\_NUM | U\*1 | Test site number | V | Raw |
| TEST\_FLG | B\*1 | Test flags (fail, alarm, etc.) | V | TestItemResult.Result |
| PARM\_FLG | B\*1 | Parametric test flags (drift, etc.) | V | Default(0) |
| RESULT | R\*4 | Test result | V | TestItemResult.Measure |
| TEST\_TXT | C\*n | Test description text or label | V | TestItemResult.PinName |
| ALARM\_ID | C\*n | Name of alarm |  |  |
| OPT\_FLAG | B\*1 | Optional data flag |  |  |
| RES\_SCAL | I\*1 | Test results scaling exponent |  |  |
| LLM\_SCAL | I\*1 | Low limit scaling exponent |  |  |
| HLM\_SCAL | I\*1 | High limit scaling exponent |  |  |
| LO\_LIMIT | R\*4 | Low test limit value | V | TestItemResult.LowLimit |
| HI\_LIMIT | R\*4 | High test limit value | V | TestItemResult.HighLimit |
| UNITS | C\*n | Test units | V | TestItemResult.MeasureUnit |
| C\_RESFMT | C\*n | ANSI C result format string |  |  |
| C\_LLMFMT | C\*n | ANSI C low limit format string |  |  |
| C\_HLMFMT | C\*n | ANSI C high limit format string |  |  |
| LO\_SPEC | R\*4 | Low specification limit value | V | Default(0) |
| HI\_SPEC | R\*4 | High specification limit value | V | Default(0) |